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| Notice of References Cited | Application/Control No. 10/088,656 | | Applicant(s)/Patent Under Reexamination WOERNER ET AL. | |
| | Examiner Tae H. Yoon | | Art Unit 1714 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-6,391,956 | 05-2002 | Horio et al. | 524/314 |
| * | B | US-5,478,895 | 12-1995 | Sugiyama et al. | 525/398 |
| * | C | US-4,780,498 | 10-1988 | Goerrissen et al. | 524/456 |
| * | D | US-4,517,319 | 05-1985 | Reske et al. | 523/200 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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